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Ignition IGBT

20 A, 365 V, N-Channel D²PAK

This Logic Level Insulated Gate Bipolar Transistor (IGBT) features monolithic circuitry integrating ESD and Overvoltage clamped protection for use in inductive coil drivers applications. Primary uses include Ignition, Direct Fuel Injection, or wherever high voltage and high current switching is required.

Features

- Ideal for Coil–on–Plug and Driver–on–Coil Applications
- Gate-Emitter ESD Protection
- Temperature Compensated Gate-Collector Voltage Clamp Limits Stress Applied to Load
- Integrated ESD Diode Protection
- Low Threshold Voltage for Interfacing Power Loads to Logic or Microprocessor Devices
- Low Saturation Voltage
- High Pulsed Current Capability
- Minimum Avalanche Energy 500 mJ
- Gate Resistor (R_G) = 70 Ω
- This is a Pb-Free Device

Applications

• Ignition Systems

MAXIMUM RATINGS (T_{.I} = 25°C unless otherwise noted)

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V _{CES}	365	V
Gate-Emitter Voltage	V _{GE}	±15	V
Collector Current–Continuous @ T _C = 25°C – Pulsed	I _C	20 50	A _{DC} A _{AC}
Continuous Gate Current	IG	1.0	mA
Transient Gate Current (t ≤ 2 ms, f ≤ 100 Hz)	IG	20	mA
ESD (Charged-Device Model)	ESD	2.0	kV
ESD (Human Body Model) R = 1500 Ω , C = 100 pF	ESD	8.0	kV
ESD (Machine Model) R = 0 Ω , C = 200 pF	ESD	500	V
Total Power Dissipation @ T _C = 25°C Derate above 25°C (Note 1)	P _D	165 1.1	W/°C
Operating & Storage Temperature Range	T _J , T _{stg}	–55 to +175	°C

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

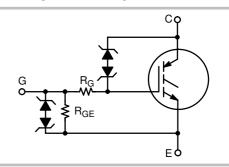
1. Assuming infinite heatsink Case-to-Ambient



ON Semiconductor®

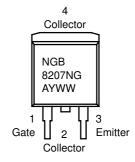
http://onsemi.com

20 AMPS 365 VOLTS $V_{CE(on)} = 1.5 \text{ V Typ } @$ $I_C = 10 \text{ A, } V_{GE} \ge 4.5 \text{ V}$





MARKING DIAGRAM



NGB8207N = Device Code

= Assembly Location

Y = Year WW = Work Week G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping [†]
NGB8207NT4G	D ² PAK (Pb-Free)	800 / Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

UNCLAMPED COLLECTOR-TO-EMITTER AVALANCHE CHARACTERISTICS $(-55^{\circ} \le T_J \le 175^{\circ}C)$

Characteristic	Symbol	Value	Unit
Single Pulse Collector–to–Emitter Avalanche Energy $V_{CC}=50~V,~V_{GE}=10~V,~Pk~I_L=16.5~A,~L=3.7~mH,~R_g=1~k\Omega~Starting~T_J=25^{\circ}C~V_{CC}=50~V,~V_{GE}=10~V,~Pk~I_L=10~A,~L=6.1~mH,~R_g=1~k\Omega~Starting~T_J=125^{\circ}C$	E _{AS}	500 306	mJ
Reverse Avalanche Energy V_{CC} = 100 V, V_{GE} = 20 V, Pk I _L = 25.8 A, L = 6.0 mH, Starting T _J = 25°C	E _{AS(R)}	2000	mJ

THERMAL CHARACTERISTICS

Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.9	°C/W
Thermal Resistance, Junction-to-Ambient (Note 2)	$R_{\theta JA}$	50	°C/W
Maximum Temperature for Soldering Purposes, 0.125 in from case for 5 seconds (Note 3)	TL	275	°C

- When surface mounted to an FR4 board using the minimum recommended pad size.
 For further details, see Soldering and Mounting Techniques Reference Manual: SOLDERRM/D.

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Temperature	Min	Тур	Max	Unit
OFF CHARACTERISTICS							
Collector-Emitter Clamp Voltage	BV _{CES}	I _C = 2.0 mA	$T_J = -40^{\circ}\text{C} \text{ to } 175^{\circ}\text{C}$	325	350	375	V
		I _C = 10 mA	$T_J = -40^{\circ}\text{C} \text{ to } 175^{\circ}\text{C}$	340	365	390	
Zero Gate Voltage Collector Current	I _{CES}	V _{CE} = 24 V V _{GE} = 0 V	T _J = 25°C		0.1	2.0	μΑ
			$T_J = 25^{\circ}C$	-	1.0	5	
		$V_{CE} = 250 \text{ V} $ $V_{GE} = 0 \text{ V}$	T _J = 175°C	70	85	150	
		TUL 5	T _J = -40°C	-	0.25	2.5	
Reverse Collector–Emitter Clamp Voltage	B _{VCES(R)}		$T_J = 25^{\circ}C$	30	33	39	V
		$I_C = -75 \text{ mA}$	T _J = 175°C	30	36	42	
			T _J = -40°C	29	32	35	
Reverse Collector–Emitter Leakage Current	I _{CES(R)}		T _J = 25°C	0.10	0.25	0.85	mA
		V _{CE} = -24 V	T _J = 175°C	20	25	40	
			$T_J = -40^{\circ}C$	-	0.03	0.3	
Gate-Emitter Clamp Voltage	BV _{GES}	$I_G = \pm 5.0 \text{ mA}$	$T_J = -40^{\circ}\text{C} \text{ to } 175^{\circ}\text{C}$	12	13	14.5	V
Gate-Emitter Leakage Current	I _{GES}	V _{GE} = ±10 V	$T_J = -40^{\circ}\text{C} \text{ to } 175^{\circ}\text{C}$	500	700	1000	μΑ
Gate Resistor	R_{G}		$T_J = -40^{\circ}\text{C} \text{ to } 175^{\circ}\text{C}$		70		Ω
Gate-Emitter Resistor	R _{GE}		$T_J = -40^{\circ}\text{C} \text{ to } 175^{\circ}\text{C}$	14.25	16	25	kΩ
ON CHARACTERISTICS (Note 4)	-	-	-	-	-	-	-
Gate Threshold Voltage	V _{GE(th)}		T _J = 25°C	1.2	1.5	2.0	V
		$I_C = 1.0 \text{ mA}$ $V_{GE} = V_{CE}$	T _J = 175°C	0.6	8.0	1.2	
		·GE - ·CE				1	1

Gate Threshold Voltage	V _{GE(th)}		T _J = 25°C	1.2	1.5	2.0	V
		$I_C = 1.0 \text{ mA}$ $V_{GE} = V_{CE}$	T _J = 175°C	0.6	0.8	1.2	
		GE GE	$T_J = -40^{\circ}C$	1.4	1.7	2.0	
Threshold Temperature Coefficient (Negative)				12	12	12	mV/°C
Collector-to-Emitter On-Voltage	V _{CE(on)}		$T_J = 25^{\circ}C$	1.0	1.3	1.6	V
		$I_{C} = 6.0 \text{ A}$ $V_{GE} = 4.0 \text{ V}$	T _J = 175°C	0.8	1.1	1.4	
		GL	$T_J = -40^{\circ}C$	1.15	1.4	1.75	
		I _C = 10 mA V _{GE} = 4.5 V	T _J = 25°C	-	0.62	1.0	

^{*}Maximum Value of Characteristic across Temperature Range.

^{4.} Pulse Test: Pulse Width \leq 300 μ S, Duty Cycle \leq 2%.

ELECTRICAL CHARACTERISTICS

Characteristic	Symbol	Test Conditions	Temperature	Min	Тур	Max	Unit
ON CHARACTERISTICS (Note 4)							
ollector-to-Emitter On-Voltage V _{CE(on)} I _C =		$T_J = 25^{\circ}C$	1.1	1.5	1.7	V	
		$I_{C} = 8.0 \text{ A}$ $V_{GE} = 4.0 \text{ V}$	T _J = 175°C	1.0	1.3	1.6	
		rge	$T_J = -40^{\circ}C$	1.2	1.5	1.85	
			$T_J = 25^{\circ}C$	1.2	1.6	1.9	
		$I_{C} = 10 \text{ A}$ $V_{GE} = 3.7 \text{ V}$	T _J = 175°C	1.1	1.45	1.8	
		GE	$T_J = -40^{\circ}C$	1.3	1.7	2.0	
			$T_J = 25^{\circ}C$	1.1	1.5	1.85	
		$I_{C} = 10 \text{ A}$ $V_{GE} = 4.0 \text{ V}$	T _J = 175°C	1.1	1.4	1.75	
		GE	$T_J = -40^{\circ}C$	1.35	1.7	2.1	
			$T_J = 25^{\circ}C$	1.2	1.5	1.8	
		$I_{C} = 10 \text{ A}$ $V_{GE} = 4.5 \text{ V}$	T _J = 175°C	1.1	1.4	1.7	
		TOL	$T_J = -40^{\circ}C$	1.2	1.6	2.0	
			$T_J = 25^{\circ}C$	1.45	1.85	2.15	
		$I_{C} = 15 \text{ A}$ $V_{GE} = 4.0 \text{ V}$	T _J = 175°C	1.6	1.9	2.4	
		VGE - 1.0 V	$T_J = -40^{\circ}C$	1.5	1.9	2.25	
			$T_J = 25^{\circ}C$	1.6	2.1	2.6	
		$I_{C} = 20 \text{ A}$ $V_{GE} = 4.0 \text{ V}$	T _J = 175°C	2.0	2.4	3.1	
		VGE - 1.0 V	$T_J = -40^{\circ}C$	1.6	2.1	2.5	
Forward Transconductance	gfs	I _C = 6.0 A V _{CE} = 5.0 V	T _J = 25°C	-	15.8	-	Mhos
DYNAMIC CHARACTERISTICS	•				•	•	•
Input Capacitance	C _{ISS}			750	810	900	pF
Output Capacitance	C _{OSS}	f = 10 kHz V _{CE} = 25 V T _J = 25°C	75	90	105		
Transfer Capacitance	C _{RSS}	VGE - 23 V	Ÿ	4	7	12	1
SWITCHING CHARACTERISTICS	-						
Turn-On Delay Time (Resistive) Low Voltage	t _{d(on)}	V _{CE} = 14 V R _L = 1.0 Ω	T _J = 25°C	0.5	0.55	0.7	μSec
Rise Time (Resistive) Low Voltage	t _r	$V_{GE} = 5.0 \text{ V}$ $R_{G} = 1000 \Omega$	T _J = 25°C	2.0	2.32	2.7	
Turn–Off Delay Time (Resistive) Low Voltage	t _{d(off)}	V _{CE} = 14 V R _L = 1.0 Ω	T _J = 25°C	2.0	2.5	3.0	
Fall Time (Resistive) Low Voltage	t _f	$V_{GE} = 5.0 \text{ V}$ $R_{G} = 1000 \Omega$	T _J = 25°C	8.0	10	13	
Turn–On Delay Time (Resistive) High Voltage	t _{d(on)}	$V_{CE} = 300 \text{ V}$ $R_{I} = 46 \Omega$	$T_J = 25^{\circ}C$	0.5	0.65	0.75	
Rise Time (Resistive) High Voltage	t _r	$V_{GE} = 5.0 \text{ V}$ $R_{G} = 1000 \Omega$	$T_J = 25^{\circ}C$	0.7	1.8	2.0	
Turn–Off Delay Time (Resistive) High Voltage	t _{d(off)}	$V_{CE} = 300 \text{ V}$ $R_{L} = 46 \Omega$	$T_J = 25^{\circ}C$	4.0	4.7	6.0	
Fall Time (Resistive) High Voltage	t _f	$V_{GE} = 5.0 \text{ V}$ $R_G = 1000 \Omega$	T _J = 25°C	6.0	10	15	

^{*}Maximum Value of Characteristic across Temperature Range. 4. Pulse Test: Pulse Width $\leq 300~\mu S$, Duty Cycle $\leq 2\%$.

TYPICAL ELECTRICAL CHARACTERISTICS

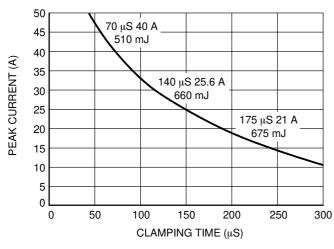


Figure 1. Typical Self Clamped Inductive Switching Performance (SCIS) @ 25°C

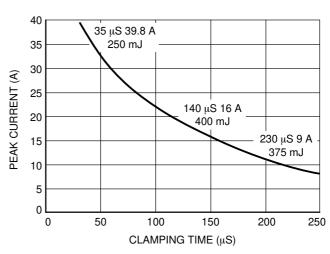


Figure 2. Typical Self Clamped Inductive Switching Performance (SCIS) @ 150°C

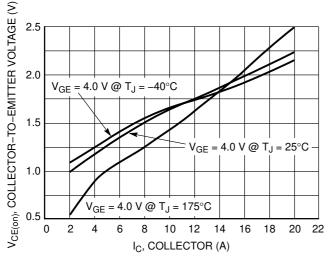


Figure 3. Collector-to-Emitter Voltage vs.
Collector Current

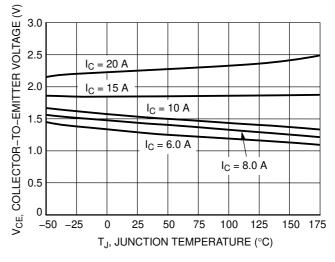


Figure 4. Collector-to-Emitter Voltage vs.
Junction Temperature

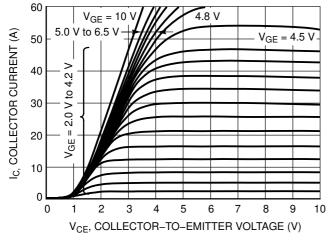


Figure 5. On–Region Characteristics $@T_J = 25^{\circ}C$

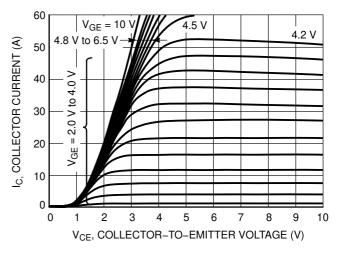


Figure 6. On–Region Characteristics $@T_J = -40^{\circ}C$

TYPICAL ELECTRICAL CHARACTERISTICS

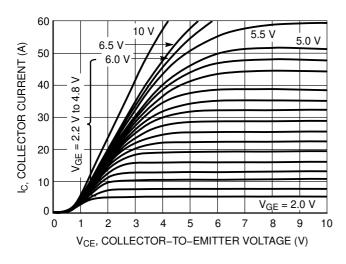
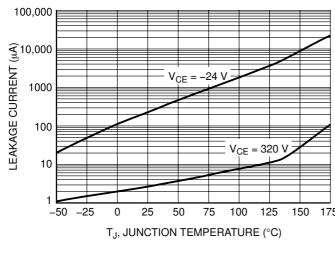


Figure 7. On–Region Characteristics @ T_J = 175°C

Figure 8. Transfer Characteristics



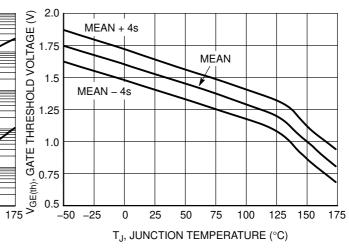
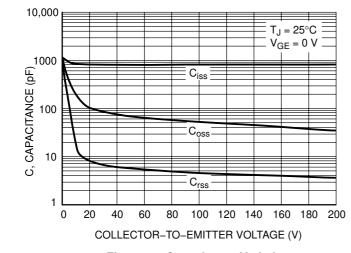


Figure 9. Collector–to–Emitter Leakage Current vs. Temperature

Figure 10. Gate Threshold Voltage vs. Temperature



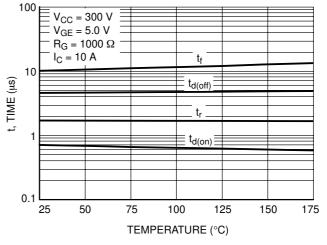


Figure 11. Capacitance Variation

Figure 12. Resistive Switching Time Variation vs. Temperature

TYPICAL ELECTRICAL CHARACTERISTICS

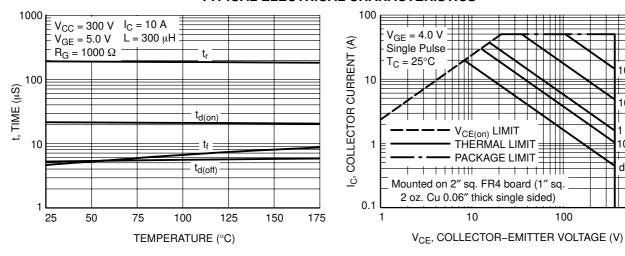


Figure 13. Inductive Switching Time Variation vs. Temperature

Figure 14. Forward Biased Safe Operating Area

10 μs

100 μs

1 ms ∏ 10 ms≢

dc | | | |

1000

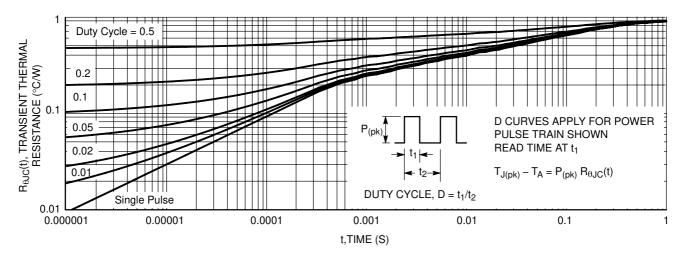
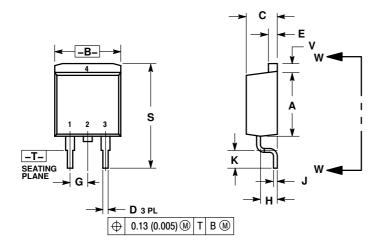


Figure 15. Best Case Transient Thermal Resistance (Non-normalized Junction-to-Case Mounted on Cold Plate)

PACKAGE DIMENSIONS

D²PAK 3 CASE 418B-04 **ISSUE J**

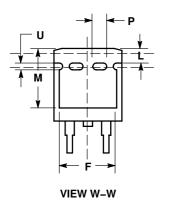


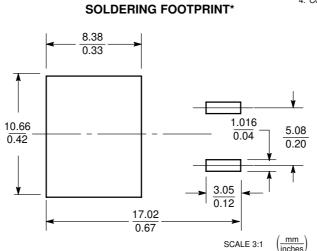
NOTES:

- DIMENSIONING AND TOLERANCING
 PER ANSI Y14.5M. 1982.
- CONTROLLING DIMENSION: INCH.
- 418B-01 THRU 418B-03 OBSOLETE, NEW STANDARD 418B-04.

	INC	HES	MILLIMETER				
DIM	MIN	MAX	MIN	MAX			
Α	0.340	0.380	8.64	9.65			
В	0.380	0.405	9.65	10.29			
С	0.160	0.190	4.06	4.83			
D	0.020	0.035	0.51	0.89			
E	0.045	0.055	1.14	1.40			
F	0.310	0.350	7.87	8.89			
G	0.100	BSC	2.54	BSC			
Н	0.080	0.110	2.03	2.79			
J	0.018	0.025	0.46	0.64			
K	0.090	0.110	2.29	2.79			
L	0.052	0.072	1.32	1.83			
М	0.280	0.320	7.11	8.13			
N	0.197	REF	5.00	REF			
Р	0.079	REF	2.00 REF				
R	0.039	REF	0.99	REF			
S	0.575	0.625	14.60	15.88			
V	0.045	0.055	1 14	1 40			

- STYLE 4: PIN 1. GATE 2. COLLECTOR 3. EMITTER
 - COLLECTOR





*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D

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